

August 2007

# FDFMJ2P023Z

# Integrated P-Channel PowerTrench® MOSFET and Schottky Diode –20V, –2.9A, 112m $\Omega$

### **Features**

# **MOSFET**

- Max  $r_{DS(on)} = 112m\Omega$  at  $V_{GS} = -4.5V$ ,  $I_D = -2.9A$
- Max  $r_{DS(on)} = 160 \text{m}\Omega$  at  $V_{GS} = -2.5 \text{V}$ ,  $I_D = -2.4 \text{A}$
- Max  $r_{DS(on)} = 210m\Omega$  at  $V_{GS} = -1.8V$ ,  $I_D = -2.1A$
- Max  $r_{DS(on)} = 300 \text{m}\Omega$  at  $V_{GS} = -1.5 \text{V}$ ,  $I_D = -1.0 \text{A}$
- Low gate charge, high power and current handline capability
- HBM ESD protection level > 1.5KV typical (Note 3)

# **Schottky**

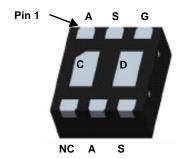
- V<sub>F</sub> < 400mV @ 100mA
- RoHS Compliant



# **General Description**

This device is designed specifically as a single package solution for the battery charge switch in cellular handset and other ultra-portable applications. It features a MOSFET with low on-state resistance and an independently connected low forward voltage schottky diode for minimum conduction losses.

The SC-75 MicroFET package offers exceptional thermal performance for it's physical size and is well suited to linear mode applications.



**SC-75 MicroFET** 

# TO BOTTOM 6 NC S 2 5 A G 3 TO BOTTOM

# MOSFET Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

| Symbol                            | Parameter   |           | Ratings     | Units |
|-----------------------------------|---|-----------|-------------|-------|
| V <sub>DS</sub>                   | Drain to Source Voltage                                     |           | -20         | V     |
| $V_{GS}$                          | Gate to Source Voltage                                      |           | ±8          | V     |
|                                   | Drain Current -Continuous                                   | (Note 1a) | -2.9        | ^     |
| I <sub>D</sub>                    | -Pulsed   |           | -12         | A     |
| В                                 | Power Dissipation   | (Note 1a) | 1.4         | W     |
| $P_{D}$                           | Power Dissipation   | (Note 1b) | 0.7         | VV    |
| T <sub>J</sub> , T <sub>STG</sub> | Operating and Storage Junction Temperature Range -55 to +15 |           | -55 to +150 | °C    |
| $V_{RRM}$                         | Schottky Repetitive Peak Reverse Voltage 30                 |           | V           |       |
| Io                                | Schottky Average Forward Current                            |           | 1           | А     |

### **Thermal Characteristics**

| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient | (Note 1a) | 89  | °C/W |
|-----------------|---|-----------|-----|------|
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient | (Note 1b) | 182 | C/VV |

# **Package Marking and Ordering Information**

| Device Marking | Device      | Package Reel Size |    | Tape Width | Quantity   |
|----------------|-------------|-------------------|----|------------|------------|
| .P23           | FDFMJ2P023Z | SC-75 MicroFET    | 7" | 8 mm       | 3000 units |

# **Electrical Characteristics** T<sub>J</sub> = 25°C unless otherwise noted

| Symbol                               | Parameter                                    | Test Conditions                              | Min | Тур | Max | Units |
|--------------------------------------|--|--|-----|-----|-----|-------|
| Off Chara                            | acteristics                                  |  |     |     |     |       |
| BV <sub>DSS</sub>                    | Drain to Source Breakdown Voltage            | $I_D = -250 \mu A, V_{GS} = 0 V$             | -20 |     |     | V     |
| $\frac{\Delta BV_{DSS}}{\Delta T_J}$ | Breakdown Voltage Temperature<br>Coefficient | $I_D = -250\mu\text{A}$ , referenced to 25°C |     | -13 |     | mV/°C |
| I <sub>DSS</sub>                     | Zero Gate Voltage Drain Current              | $V_{DS} = -16V, V_{GS} = 0V$                 |     |     | -1  | μΑ    |
| I <sub>GSS</sub>                     | Gate to Source Leakage Current               | $V_{GS} = \pm 8V$ , $V_{DS} = 0V$            |     |     | ±10 | μΑ    |

# **On Characteristics**

| V <sub>GS(th)</sub>                    | Gate to Source Threshold Voltage                         | $V_{GS} = V_{DS}, I_{D} = -250 \mu A$             | -0.4 | -0.7 | -1.0 | V     |
|--|--|---|------|------|------|-------|
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate to Source Threshold Voltage Temperature Coefficient | $I_D = -250\mu\text{A}$ , referenced to 25°C      |      | 2.3  |      | mV/°C |
|  | $V_{GS} = -4.5V, I_D = -2.9A$                            |   | 93   | 112  |      |       |
|  |  | $V_{GS} = -2.5V$ , $I_D = -2.4A$                  |      | 128  | 160  |       |
| r <sub>DS(on)</sub>                    | Static Drain to Source On Resistance                     | $V_{GS} = -1.8V, I_D = -2.1A$                     |      | 173  | 210  | mΩ    |
|  |  | $V_{GS} = -1.5V$ , $I_D = -1.0A$                  |      | 217  | 300  |       |
|  |  | $V_{GS} = -4.5V$ , $I_D = -2.9A$ , $T_J = 125$ °C |      | 130  | 160  |       |
| 9 <sub>FS</sub>                        | Forward Transconductance                                 | $V_{DS} = -5V, I_{D} = -2.9A$                     |      | 7    |      | S     |

# **Dynamic Characteristics**

| C <sub>iss</sub> | Input Capacitance            | V 40V V 0V                                | 300 | 400 | pF |
|------------------|------------------------------|---|-----|-----|----|
| C <sub>oss</sub> | Output Capacitance           | $V_{DS} = -10V, V_{GS} = 0V,$<br>f = 1MHz | 55  | 75  | pF |
| C <sub>rss</sub> | Reverse Transfer Capacitance | 1 = 11/11/12                              | 45  | 70  | pF |

# **Switching Characteristics**

| t <sub>d(on)</sub>  | Turn-On Delay Time            |   | 5   | 10  | ns |
|---------------------|-------------------------------|---|-----|-----|----|
| t <sub>r</sub>      | Rise Time                     | $V_{DD} = -10V, I_{D} = -2.9A$<br>$V_{GS} = -4.5V, R_{GEN} = 6\Omega$ | 4   | 10  | ns |
| t <sub>d(off)</sub> | Turn-Off Delay Time           | $V_{GS} = -4.5V, R_{GEN} = 0.02$                                      | 23  | 37  | ns |
| t <sub>f</sub>      | Fall Time                     |   | 12  | 22  | ns |
| Qg                  | Total Gate Charge             | V 5V 1 0.04   | 4.6 | 6.5 | nC |
| Q <sub>gs</sub>     | Gate to Source Charge         | $V_{DD} = -5V, I_{D} = -2.9A$<br>- $V_{GS} = -4.5V$                   | 0.6 |     | nC |
| Q <sub>gd</sub>     | Gate to Drain "Miller" Charge | VGS - 4.5V  | 1.0 |     | nC |

# **Drain-Source Diode Characteristics**

| I <sub>S</sub>  | Maximum Continuous Drain-Source Diode Forward Current |   |      | -1.1 | Α  |
|-----------------|---|---|------|------|----|
| $V_{SD}$        | Source to Drain Diode Forward Voltage                 | $V_{GS} = 0V, I_S = -1.1A$                        | -0.9 | -1.2 | V  |
| t <sub>rr</sub> | Reverse Recovery Time                                 | $I_{\rm F} = -2.9$ A, di/dt = 100A/µs             | 28   | 45   | ns |
| Q <sub>rr</sub> | Reverse Recovery Charge                               | $-1F = -2.9A$ , $\text{di/dt} = 100A/\mu\text{S}$ | 15   | 27   | nC |

# **Electrical Characteristics** $T_J = 25^{\circ}C$ unless otherwise noted

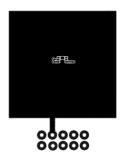
| Symbol | Parameter | Test Conditions | Min | Тур | Max | Units |
|--------|-----------|-----------------|-----|-----|-----|-------|
|        |           |                 |     |     |     |       |

# **Schottky Diode Characteristics**

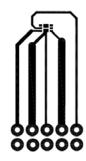
| $V_R$   | Reverse Voltage | I <sub>R</sub> = 100mA  | $T_J = 25^{\circ}C$ | 30 |      |     | V  |
|---------|-----------------|-------------------------|---------------------|----|------|-----|----|
|         |                 |                         | $T_J = 25^{\circ}C$ |    | 0.39 | 2   | μΑ |
| $I_R$   | Reverse Leakage | $V_R = 10V$             | $T_J = 85^{\circ}C$ |    | 0.04 | 0.2 | mA |
|         |                 |                         | $T_J = 125$ °C      |    | 0.4  | 2   | mA |
|         |                 |                         | $T_J = 25^{\circ}C$ |    | 0.86 | 4   | μΑ |
| $I_R$   | Reverse Leakage | $V_R = 20V$             | $T_J = 85^{\circ}C$ |    | 0.06 | 0.3 | mA |
|         |                 |                         | $T_J = 125$ °C      |    | 0.62 | 3   | mA |
|         |                 |                         | $T_J = 25^{\circ}C$ |    | 380  | 400 | mV |
| $V_{F}$ | Forward Voltage | $I_{F} = 100 \text{mA}$ | $T_J = 85^{\circ}C$ |    | 300  | 350 | mV |
|         |                 |                         | $T_J = 125$ °C      |    | 250  | 300 | mV |
|         |                 |                         | $T_J = 25^{\circ}C$ |    | 570  | 615 | mV |
| $V_{F}$ | Forward Voltage | $I_F = 1A$              | $T_J = 85^{\circ}C$ |    | 540  | 590 | mV |
|         |                 |                         | $T_J = 125$ °C      |    | 530  | 580 | mV |

### Notes

1. R<sub>BJA</sub> is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>BJC</sub> is guaranteed by design while R<sub>BCA</sub> is determined by the user's board design.



a. 89°C/W when mounted on a 1 in² pad of 2 oz copper



b.182°C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300 $\mu$ s, Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

# Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

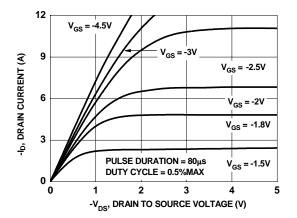


Figure 1. On-Region Characteristics

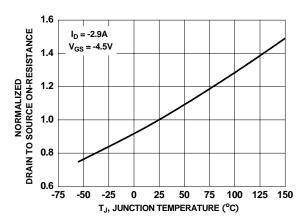


Figure 3. Normalized On-Resistance vs Junction Temperature

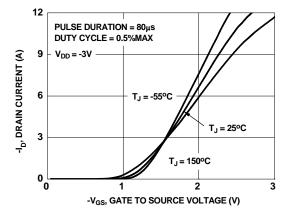


Figure 5. Transfer Characteristics

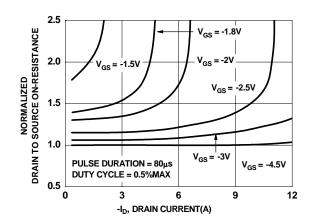


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

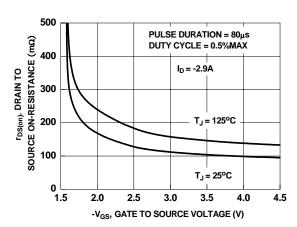


Figure 4. On-Resistance vs Gate to Source Voltage

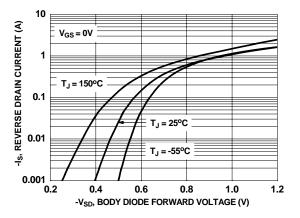


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

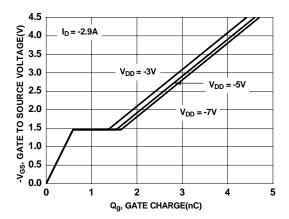


Figure 7. Gate Charge Characteristics

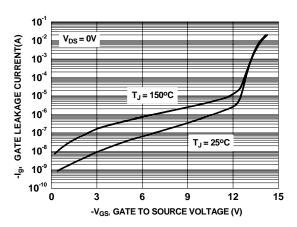


Figure 9. Gate Leakage Current vs Gate to Source Voltage

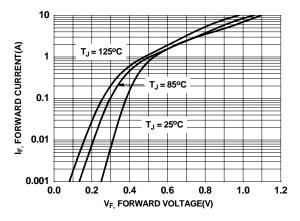


Figure 11. Schottky Diode Forward Voltage

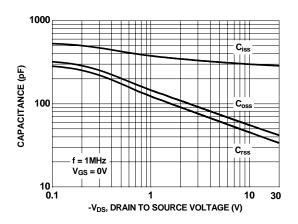


Figure 8. Capacitance vs Drain to Source Voltage

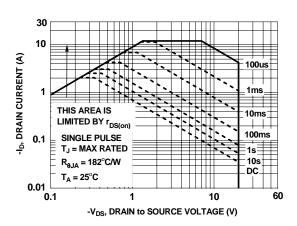


Figure 10. Forward Bias Safe Operating Area

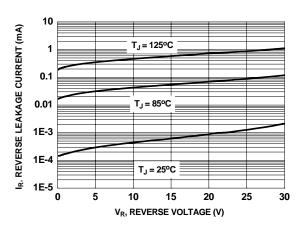


Figure 12. Schottky Diode Reverse Current

# **Typical Characteristics** T<sub>J</sub> = 25°C unless otherwise noted

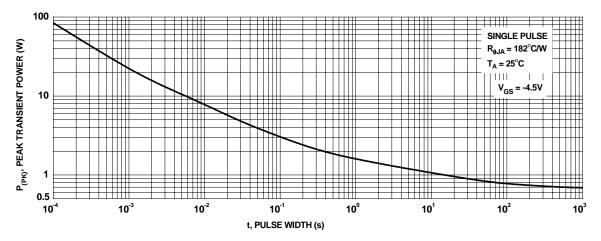


Figure 13. Single Pulse Maximum Power Dissipation

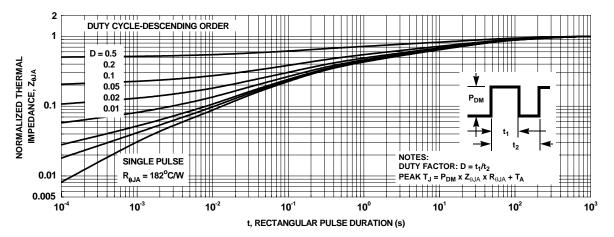
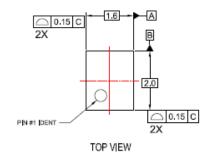
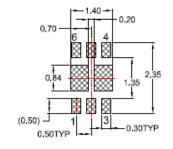


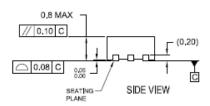
Figure 14. Transient Thermal Response Curve

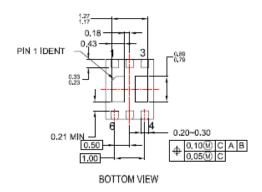
# **Dimensional Outline and Pad Layout**





RECOMMENDED LAND PATTERN







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